

UTC UNISONIC TECHNOLOGIES CO., LTD

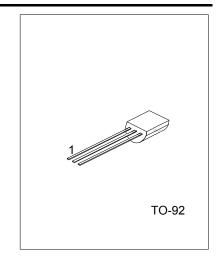
1N50Z **Preliminary Power MOSFET**

1.3A, 500V N-CHANNEL POWER MOSFET

DESCRIPTION

The UTC 1N50Z is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

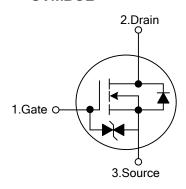
The UTC 1N50Z is generally applied in high efficiency switch mode power supplies, active power factor correction and electronic lamp ballasts based on half bridge topology.



FEATURES

- * $R_{DS(ON)}$ =4.6 Ω @ V_{GS} =10V
- * High Switching Speed
- * 100% Avalanche Tested

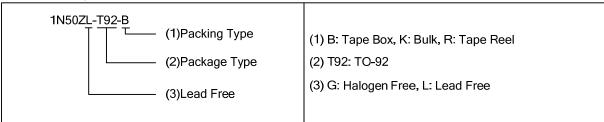
SYMBOL



ORDERING INFORMATION

Ordering Number		Dookogo	Pin	Dooking			
Lead Free	Halogen Free	Package	1	2	3	Packing	
1N50ZL-T92-B	1N50ZG-T92-B	TO-92	G	D	S	Tape Box	
1N50ZL-T92-K	1N50ZG-T92-K	TO-92	G	D	S	Bulk	
1N50ZL-T92-R	1N50ZG-T92-R	TO-92	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



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■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	500	V
Gate-Source Voltage		V_{GSS}	±20	V
Drain Current	Continuous (T _C =25°C)	I_{D}	1.3 (Note 2)	Α
	Pulsed (Note 3)	I_{DM}	5 (Note 2)	Α
Avalanche Current (Note 3)		I _{AR}	1.3	Α
Avalanche Energy	Single Pulsed (Note 4)	E _{AS}	113	mJ
	Repetitive (Note 5)	E _{AR}	2.6	mJ
Power Dissipation		Ь	40	W
Derate above 25°C		P_{D}	0.32	W/°C
Junction Temperature		T_J	+150	°C
Storage Temperature		T _{STG}	-55~+150	°C

Note: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Drain current limited by maximum junction temperature
- 3. Repetitive Rating: Pulse width limited by maximum junction temperature
- 4. L = 120mH, I_{AS} = 1.3A, V_{DD} = 50V, R_G = 27 Ω , Starting T_J = 25°C
- 5. $I_{SD} \le 1.5A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	62.5	°C/W
Junction to Case	$\theta_{ m JC}$	3.13	°C/W

■ **ELECTRICAL CHARACTERISTICS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV_{DSS}	I _D =250μA, V _{GS} =0V	500			V	
Drain-Source Leakage Current		I _{DSS}	V _{DS} =500V, V _{GS} =0V			1	μΑ	
Gate- Source Leakage Current	Forward	l less	V _{GS} =+20V, V _{DS} =0V			+5	μΑ	
	Reverse		V _{GS} =-20V, V _{DS} =0V			-5	μΑ	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.0		4.0	V	
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =0.65A		4.6	6.0	Ω	
DYNAMIC PARAMETERS								
Input Capacitance		C _{ISS}			220	290	pF	
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		30	35	pF	
Reverse Transfer Capacitance		C_{RSS}	1			13	pF	

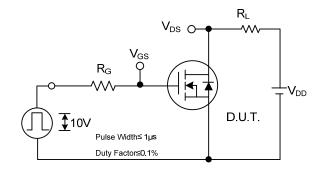
■ ELECTRICAL CHARACTERISTICS(Cont.)

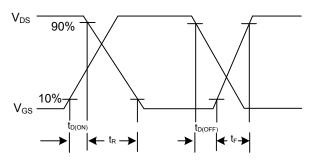
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
SWITCHING PARAMETERS								
Total Gate Charge	Q_{G}	100/1/ 400// 4.54		11	16	nC		
Gate to Source Charge	Q_GS	V _{GS} =10V, V _{DS} =400V, I _D =1.5A		1.6		nC		
Gate to Drain Charge	Q_GD	(Note 1, 2)		5.5		nC		
Turn-ON Delay Time	$t_{D(ON)}$	V_{DD} =250V, I_{D} =1.5A, R_{G} =25 Ω (Note 1, 2)		12	35	ns		
Rise Time	t_R			13	35	ns		
Turn-OFF Delay Time	t _{D(OFF)}			42	90	ns		
Fall-Time	t_{F}			15	40	ns		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current	Is				1.3	Α		
Maximum Body-Diode Pulsed Current	I _{SM}				5	Α		
Drain-Source Diode Forward Voltage	V_{SD}	I _S =1.3A, V _{GS} =0V			1.15	V		
Body Diode Reverse Recovery Time	t _{rr}	I _S =1.5A, V _{GS} =0V,		162		ns		
Body Diode Reverse Recovery Charge	Q_{RR}	dI _F /dt=100A/μs (Note 1)		0.54		μC		

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

2. Essentially independent of operating temperature

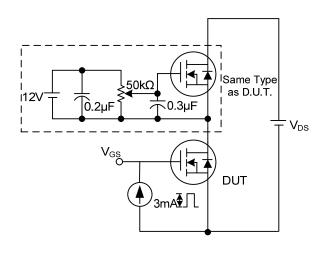
■ TEST CIRCUITS AND WAVEFORMS

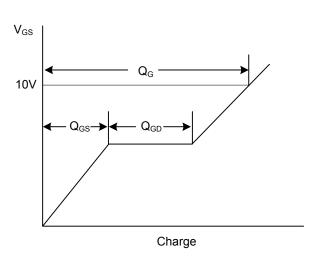




Switching Test Circuit

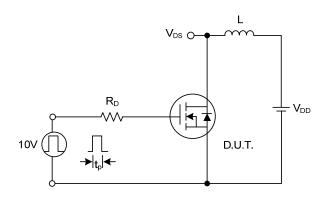
Switching Waveforms

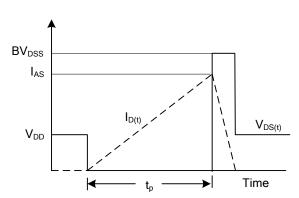




Gate Charge Test Circuit

Gate Charge Waveform

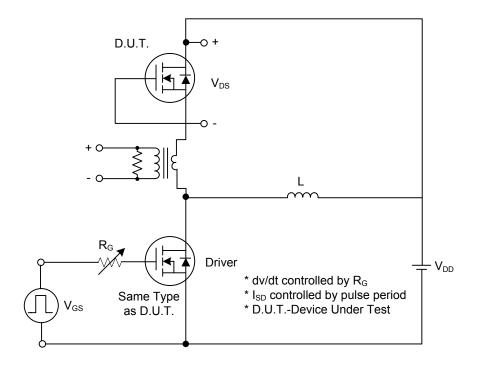




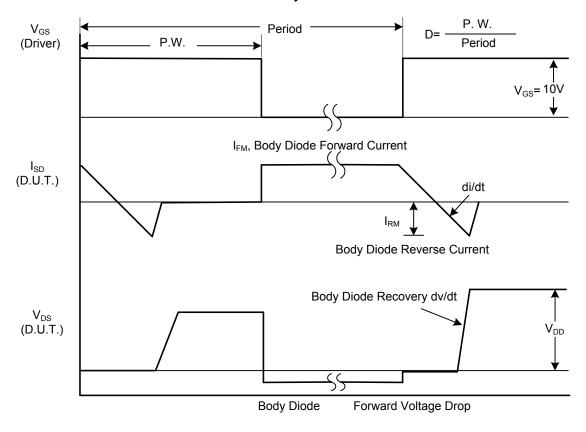
Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

■ TEST CIRCUITS AND WAVEFORMS(Cont.)



Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

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